



## 8N50-MT

Power MOSFET

### 8A, 500V N-CHANNEL POWER MOSFET

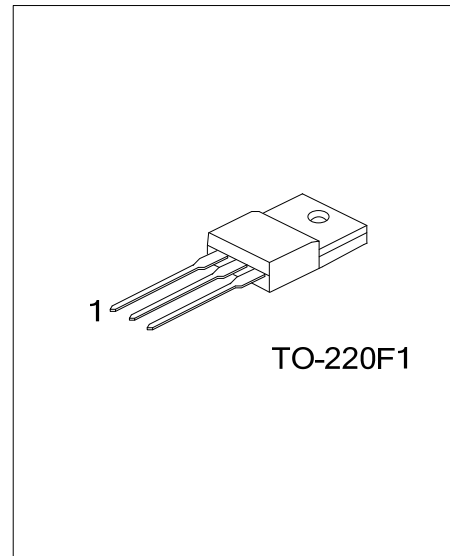
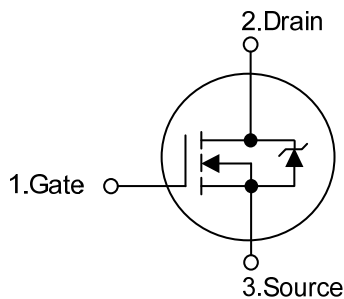
#### DESCRIPTION

The N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as switching regulators, switching converters, solenoid, motor drivers, relay drivers.

#### FEATURES

- \* Low  $R_{DS(ON)} < 0.87\Omega @ V_{GS}=10V, I_D = 4.4A$
- \* Single Pulse Avalanche Energy Rated
- \* Fast Switching Speeds
- \* Linear Transfer Characteristics
- \* High Input Impedance

#### SYMBOL



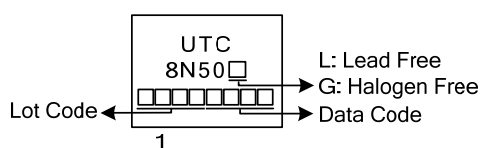
#### ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen-Free		1	2	3	
8N50L-TF1-T	8N50G-TF1-T	TO-220F1	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

	<p>(1) T: Tube</p> <p>(2) TF1: TO-220F1</p> <p>(3) G: Halogen Free and Lead Free, L: Lead Free</p>
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#### MARKING



■ ABSOLUTE MAXIMUM RATINGS ( $T_C = 25^\circ\text{C}$ , unless Otherwise Specified)

PARAMETER	SYMBOL	RATINGS	UNIT	
Drain to Source Voltage ( $T_J = 25^\circ\text{C} \sim 125^\circ\text{C}$ )	$V_{DSS}$	500	V	
Drain to Gate Voltage ( $R_{GS} = 20\text{k}\Omega$ , $T_J = 25^\circ\text{C} \sim 125^\circ\text{C}$ )	$V_{DGR}$	500	V	
Gate to Source Voltage	$V_{GSS}$	$\pm 30$	V	
Drain Current (Note 2)	Continuous	$I_D$	8.0	A
	Pulsed	$I_{DM}$	32	A
Single Pulse Avalanche Energy (Note 3)	$E_{AS}$	336	mJ	
Peak Diode Recovery dv/dt (Note 4)	dv/dt	3.3	V/ns	
Power Dissipation	$P_D$	44	W	
Junction Temperature	$T_J$	+150	$^\circ\text{C}$	
Storage Temperature	$T_{STG}$	-55 ~ +150	$^\circ\text{C}$	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3.  $L = 10\text{mH}$ ,  $I_{AS} = 8.0\text{A}$ ,  $V_{DD} = 50\text{V}$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$ .

4.  $I_{SD} \leq 8.0\text{A}$ ,  $di/dt \leq 200\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$ .

■ THERMAL DATA

PARAMETER	SYMBOL	RATING	UNIT
Junction to Ambient	$\theta_{JA}$	62.5	$^\circ\text{C}/\text{W}$
Junction to Case	$\theta_{JC}$	2.7	$^\circ\text{C}/\text{W}$

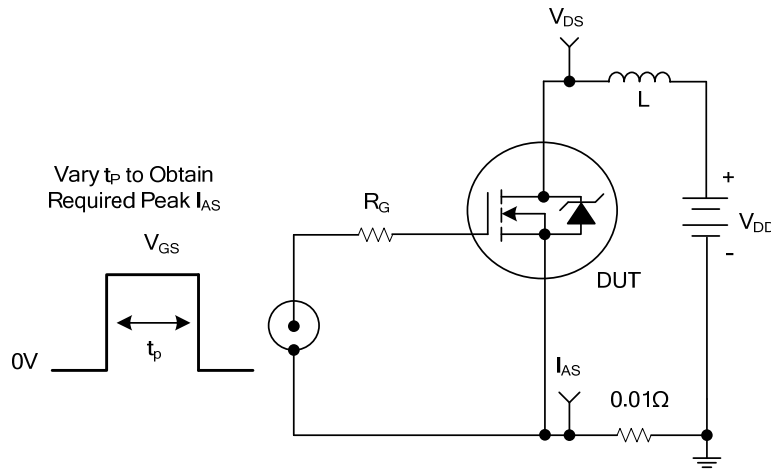
■ ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$I_D = 250\mu\text{A}$ , $V_{GS} = 0\text{V}$	500			V
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS} = \text{Rated } BV_{DSS}$ , $V_{GS} = 0\text{V}$			25	$\mu\text{A}$
Gate-Source Leakage Current	Forward	$I_{GSS}$			+100	nA
<b>ON CHARACTERISTICS</b>						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}$ , $I_D = 250\mu\text{A}$	2.0		4.0	V
Static Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS} = 10\text{V}$ , $I_D = 4.4\text{A}$			0.87	$\Omega$
<b>DYNAMIC PARAMETERS</b>						
Input Capacitance	$C_{ISS}$	$V_{GS} = 0\text{V}$ , $V_{DS} = 25\text{V}$ , $f = 1.0\text{MHz}$		920		pF
Output Capacitance	$C_{OSS}$			105		pF
Reverse Transfer Capacitance	$C_{RSS}$			10		pF
<b>SWITCHING PARAMETERS</b>						
Total Gate Charge (Note 1)	$Q_G$	$V_{DS} = 400\text{V}$ , $V_{GS} = 10\text{V}$ , $I_D = 8\text{A}$ , $I_G = 10\text{mA}$ (Note 1, 2)		24		nC
Gate to Source Charge	$Q_{GS}$			3		nC
Gate to Drain Charge	$Q_{GD}$			2		nC
Turn-on Delay Time (Note 1)	$t_{D(ON)}$	$V_{DS} = 250\text{V}$ , $V_{GS} = 10\text{V}$ , $I_D = 8\text{A}$ , $R_G = 25\Omega$ (Note 1, 2)		4.8		ns
Rise Time	$t_R$			11.6		ns
Turn-off Delay Time	$t_{D(OFF)}$			56		ns
Fall-Time	$t_F$			20		ns
<b>SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS</b>						
Maximum Body-Diode Continuous Current	$I_S$				8	A
Maximum Body-Diode Pulsed Current	$I_{SM}$				32	A
Drain-Source Diode Forward Voltage (Note 1)	$V_{SD}$	$I_S = 8.0\text{A}$ , $V_{GS} = 0\text{V}$			2	V
Reverse Recovery Time (Note 1)	$t_{rr}$	$I_S = 8.0\text{A}$ , $V_{GS} = 0\text{V}$ ,		312		nS
Reverse Recovery Charge	$Q_{rr}$	$di/dt = 100\text{A}/\mu\text{s}$		3.1		$\mu\text{C}$

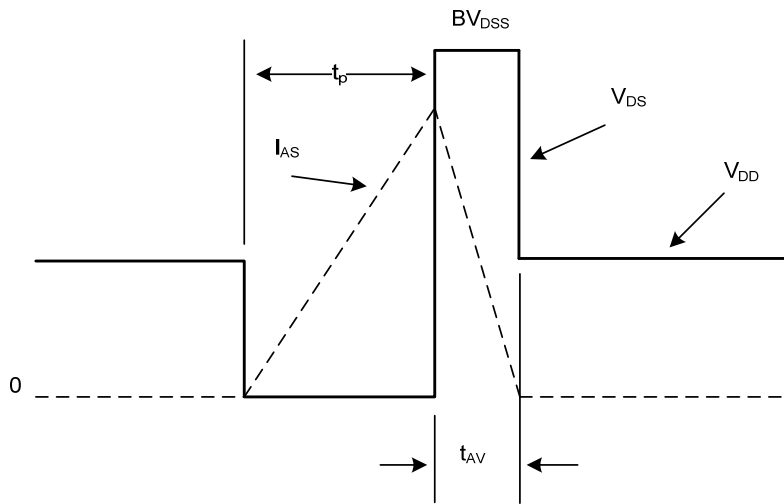
Notes: 1. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty cycle  $\leq 2\%$ .

2. Essentially independent of operating temperature.

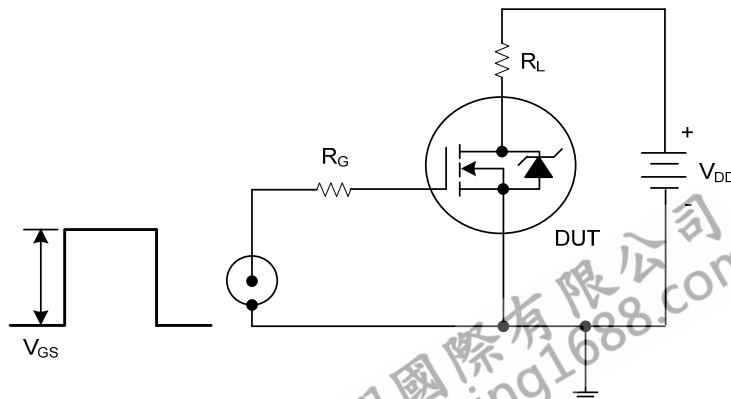
■ TEST CIRCUITS AND WAVEFORMS



Unclamped Energy Test Circuit

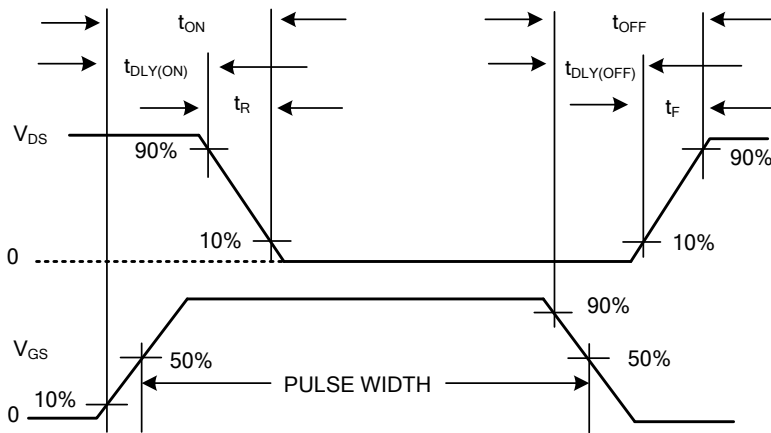


Unclamped Energy Waveforms

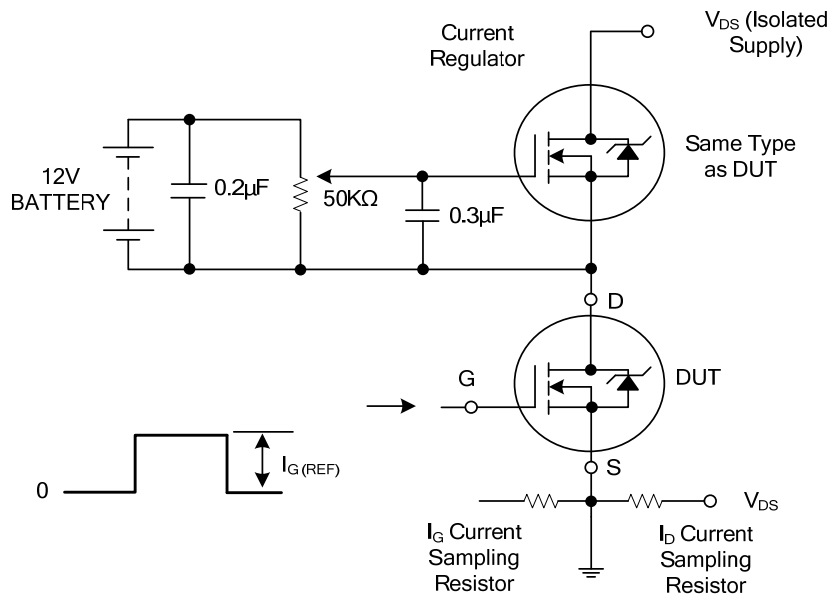


Switching Time Test Circuit

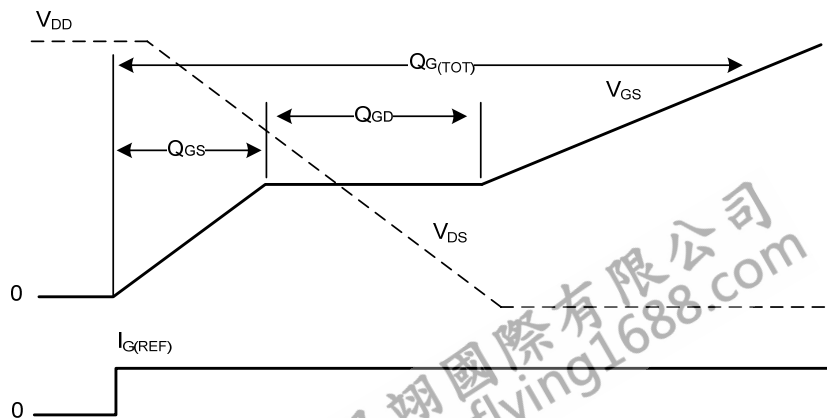
■ TEST CIRCUITS AND WAVEFORMS (Cont.)



Resistive Switching Waveforms

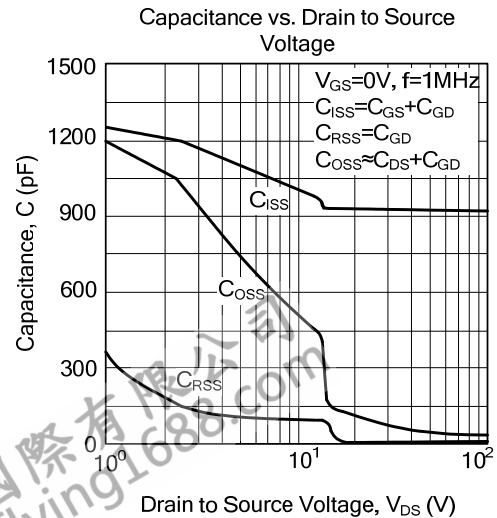
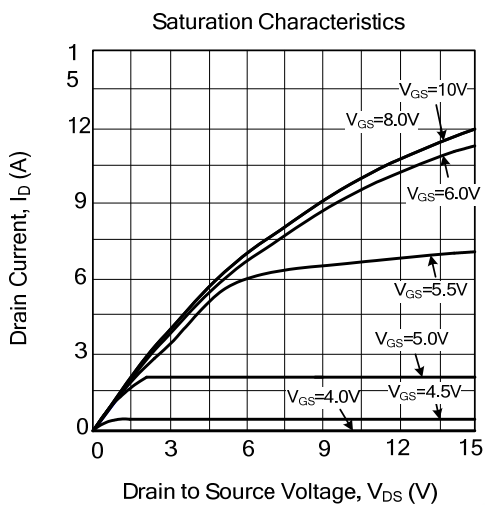
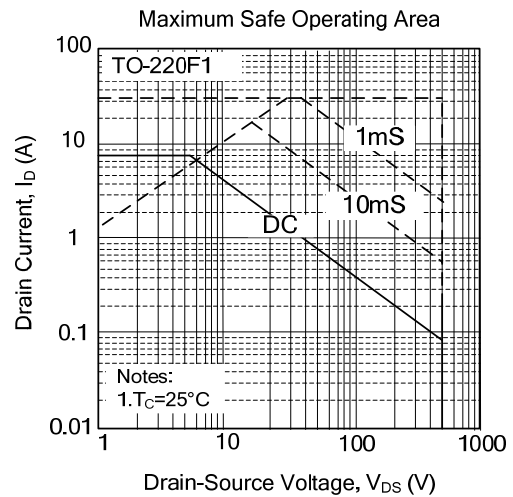
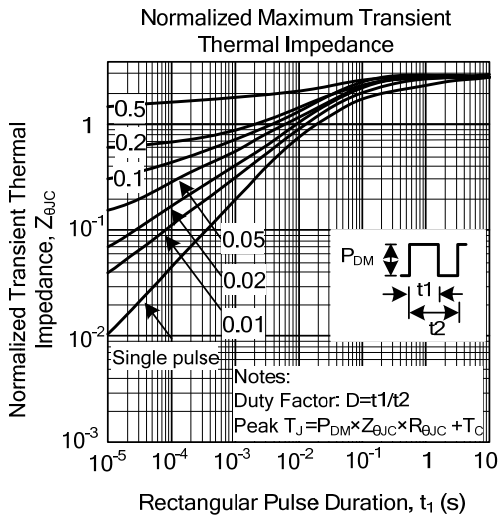
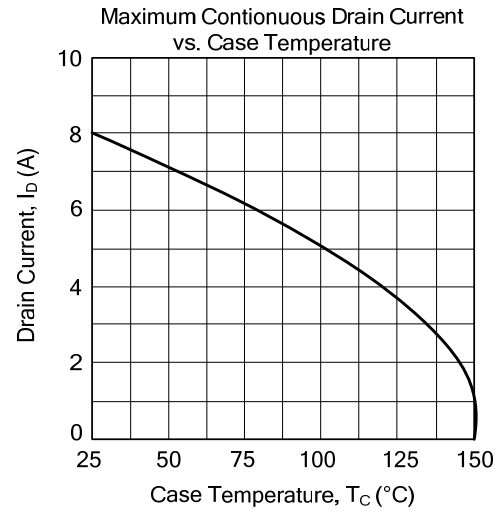
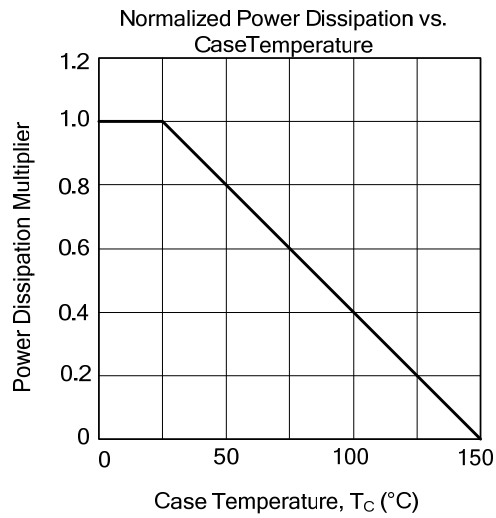


Gate Charge Test Circuit

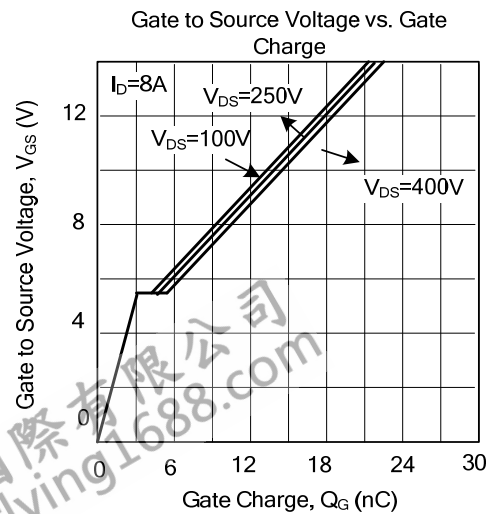
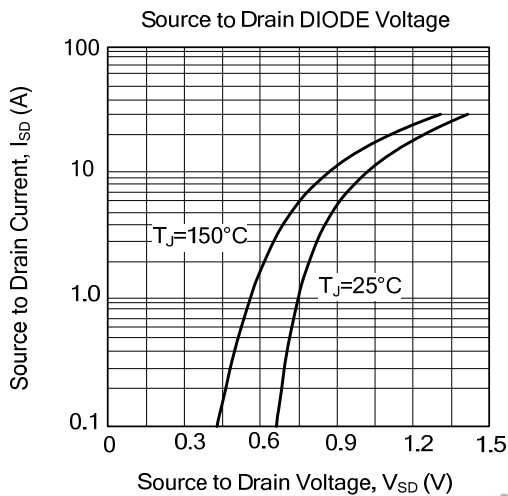
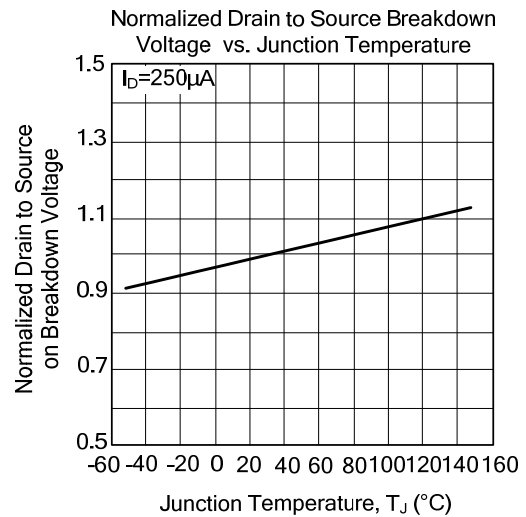
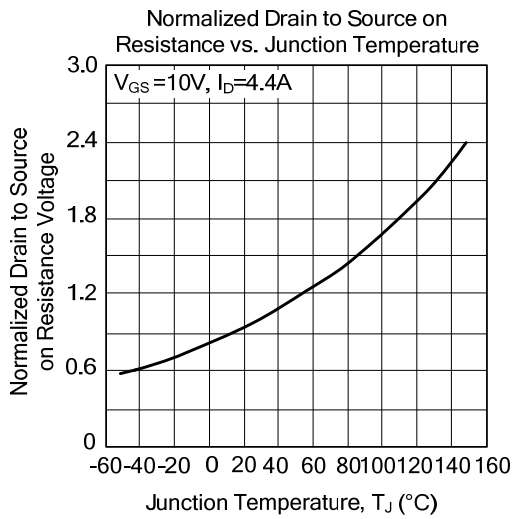
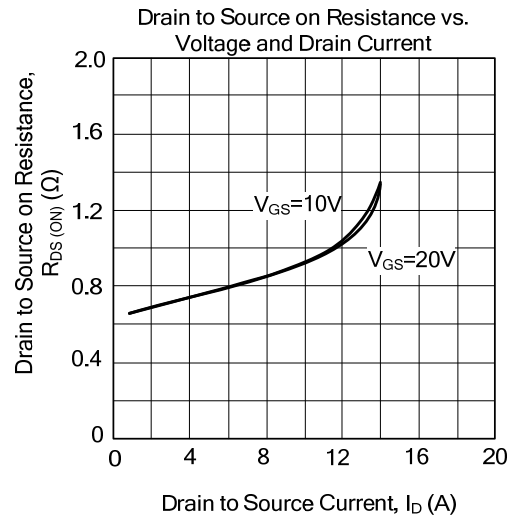
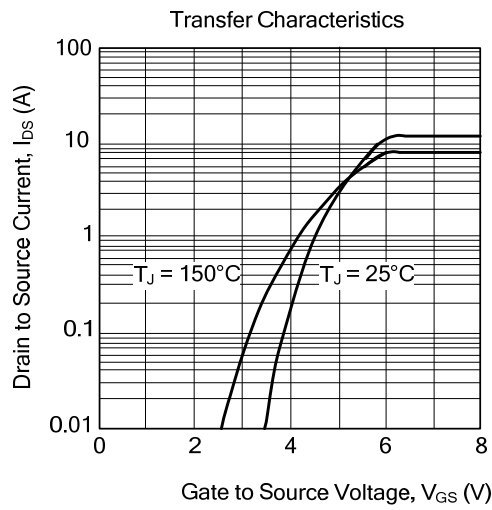


Gate Charge Waveforms

## TYPICAL CHARACTERISTICS



■ TYPICAL CHARACTERISTICS (Cont.)



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